Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/841,097	YOSHIMURA ET AL.	
Examiner	Art Unit	
Sargon N. Nano	2157	

SEARCHED			
Class	Subclass	Date	Examiner
709	223,224 226,228	7/28/2005	SN
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
EAST (see attached report)	7/28/2005	SN
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